

DATA SHEET

74ABT20

Dual 4-input NAND gate

Product specification

1995 Sep 22

IC23 Data Handbook

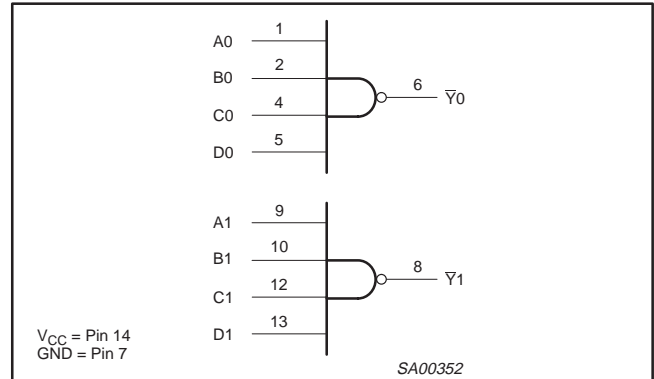
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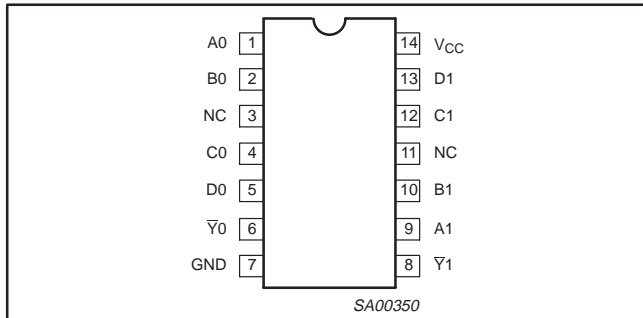
QUICK REFERENCE DATA

| SYMBOL | PARAMETER | CONDITIONS $T_{amb} = 25^{\circ}\text{C};$ $\text{GND} = 0\text{V}$ | TYPICAL | UNIT |
|--------------------------|---|---|---------|---------------|
| t_{PLH} t_{PHL} | Propagation delay A_n, B_n, C_n, D_n to \bar{Y}_n | $C_L = 50\text{pF};$ $V_{CC} = 5\text{V}$ | 2.7 | ns |
| t_{OSLH} t_{OSHL} | Output to Output skew | | 0.3 | |
| C_{IN} | Input capacitance | $V_I = 0\text{V}$ or V_{CC} | 3 | pF |
| I_{CC} | Total supply current | Outputs disabled; $V_{CC} = 5.5\text{V}$ | 50 | μA |

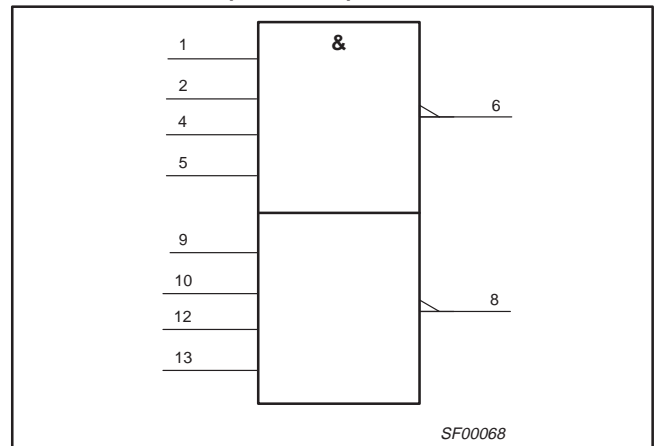
LOGIC DIAGRAM



PIN CONFIGURATION



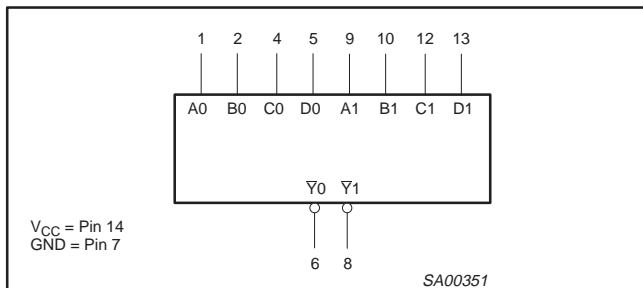
LOGIC SYMBOL (IEEE/IEC)



PIN DESCRIPTION

| PIN NUMBER | SYMBOL | NAME AND FUNCTION |
|---------------------------|----------------------|-------------------------|
| 1, 2, 4, 5, 9, 10, 12, 13 | A_n, B_n, C_n, D_n | Data inputs |
| 6, 8 | \bar{Y}_n | Data outputs |
| 7 | GND | Ground (0V) |
| 14 | V_{CC} | Positive supply voltage |

LOGIC SYMBOL



FUNCTION TABLE

| INPUTS | | | | OUTPUT |
|--------|-------|-------|-------|-------------|
| A_n | B_n | C_n | D_n | \bar{Y}_n |
| L | X | X | X | H |
| X | L | X | X | H |
| X | X | L | X | H |
| X | X | X | L | H |
| H | H | H | H | L |

NOTES:

- H = High voltage level
- L = Low voltage level
- X = Don't care

ORDERING INFORMATION

| PACKAGES | TEMPERATURE RANGE | OUTSIDE NORTH AMERICA | NORTH AMERICA | DWG NUMBER |
|-----------------------------|-------------------|-----------------------|---------------|------------|
| 14-Pin Plastic DIP | -40°C to +85°C | 74ABT20 N | 74ABT20 N | SOT27-1 |
| 14-Pin plastic SO | -40°C to +85°C | 74ABT20 D | 74ABT20 D | SOT108-1 |
| 14-Pin Plastic SSOP Type II | -40°C to +85°C | 74ABT20 DB | 74ABT20 DB | SOT337-1 |
| 14-Pin Plastic TSSOP Type I | -40°C to +85°C | 74ABT20 PW | 74ABT20PW DH | SOT402-1 |

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ABSOLUTE MAXIMUM RATINGS^{1, 2}

| SYMBOL | PARAMETER | CONDITIONS | RATING | UNIT |
|------------------|--------------------------------|-----------------------------|--------------|------|
| V _{CC} | DC supply voltage | | -0.5 to +7.0 | V |
| I _{IK} | DC input diode current | V _I < 0 | -18 | mA |
| V _I | DC input voltage ³ | | -1.2 to +7.0 | V |
| I _{OK} | DC output diode current | V _O < 0 | -50 | mA |
| V _{OUT} | DC output voltage ³ | output in Off or High state | -0.5 to +5.5 | V |
| I _{OUT} | DC output current | output in Low state | 40 | mA |
| T _{stg} | Storage temperature range | | -65 to 150 | °C |

NOTES:

- Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150°C.
- The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

RECOMMENDED OPERATING CONDITIONS

| SYMBOL | PARAMETER | LIMITS | | UNIT |
|------------------|--------------------------------------|--------|-----------------|------|
| | | MIN | MAX | |
| V _{CC} | DC supply voltage | 4.5 | 5.5 | V |
| V _I | Input voltage | 0 | V _{CC} | V |
| V _{IH} | High-level input voltage | 2.0 | | V |
| V _{IL} | Low-level input voltage | | 0.8 | V |
| I _{OH} | High-level output current | | -15 | mA |
| I _{OL} | Low-level output current | | 20 | mA |
| Δt/Δv | Input transition rise or fall rate | 0 | 10 | ns/V |
| T _{amb} | Operating free-air temperature range | -40 | +85 | °C |

DC ELECTRICAL CHARACTERISTICS

| SYMBOL | PARAMETER | TEST CONDITIONS | LIMITS | | | | UNIT | |
|------------------|--|--|--------------------------|-------|------|-----------------------------------|------|-----|
| | | | T _{amb} = +25°C | | | T _{amb} = -40°C to +85°C | | |
| | | | MIN | TYP | MAX | MIN | | MAX |
| V _{IK} | Input clamp voltage | V _{CC} = 4.5V; I _{IK} = -18mA | | -0.9 | -1.2 | | -1.2 | V |
| V _{OH} | High-level output voltage | V _{CC} = 4.5V; I _{OH} = -15mA; V _I = V _{IL} or V _{IH} | 2.5 | 2.9 | | 2.5 | | V |
| V _{OL} | Low-level output voltage | V _{CC} = 4.5V; I _{OL} = 20mA; V _I = V _{IL} or V _{IH} | | 0.35 | 0.5 | | 0.5 | V |
| I _I | Input leakage current | V _{CC} = 5.5V; V _I = GND or 5.5V | | ±0.01 | ±1.0 | | ±1.0 | μA |
| I _{OFF} | Power-off leakage current | V _{CC} = 0.0V; V _O or V _I ≤ 4.5V | | ±5.0 | ±100 | | ±100 | μA |
| I _{CEX} | Output High leakage current | V _{CC} = 5.5V; V _O = 5.5V; V _I = GND or V _{CC} | | 5.0 | 50 | | 50 | μA |
| I _O | Output current ¹ | V _{CC} = 5.5V; V _O = 2.5V | -50 | -75 | -180 | -50 | -180 | mA |
| I _{CC} | Quiescent supply current | V _{CC} = 5.5V; V _I = GND or V _{CC} | | 2 | 50 | | 50 | μA |
| ΔI _{CC} | Additional supply current per input pin ² | V _{CC} = 5.5V; One data input at 3.4V, other inputs at V _{CC} or GND | | 0.25 | 500 | | 500 | μA |

NOTES:

- Not more than one output should be tested at a time, and the duration of the test should not exceed one second.
- This is the increase in supply current for each input at 3.4V.
- For valid test results, data must not be loaded into the flip-flop or latch after applying the power.

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AC CHARACTERISTICS

GND = 0V; $t_R = t_F = 2.5\text{ns}$; $C_L = 50\text{pF}$, $R_L = 500\Omega$

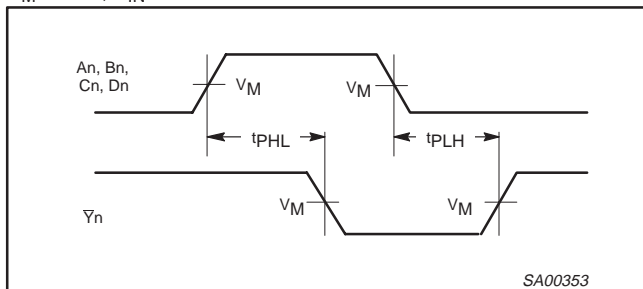
| SYMBOL | PARAMETER | WAVEFORM | LIMITS | | | | | UNIT |
|--|--|----------|--|-----|-----|--|-----|------|
| | | | $T_{\text{amb}} = +25^\circ\text{C}$ $V_{\text{CC}} = +5.0\text{V}$ | | | $T_{\text{amb}} = -40^\circ\text{C to } +85^\circ\text{C}$ $V_{\text{CC}} = +5.0\text{V} \pm 0.5\text{V}$ | | |
| | | | MIN | TYP | MAX | MIN | MAX | |
| t_{PLH} t_{PHL} | Propagation delay An, Bn, Cn, Dn to \bar{Y}_n | 1 | 1.0 | 2.7 | 3.9 | 1.0 | 4.6 | ns |
| t_{OSHL} t_{OSLH} | Output to Output skew An or Bn to \bar{Y}_n | 2 | | 0.3 | 0.5 | | 0.5 | ns |

NOTE:

- Skew is defined as the absolute value of the difference between the actual propagation delay for any two separate outputs of the same device. The specification applies to any outputs switching in the the same direction, either HIGH-to-LOW (t_{OSHL}) or LOW-to-HIGH (t_{OSLH}); parameter guaranteed by design.

AC WAVEFORMS

$V_M = 1.5\text{V}$, $V_{\text{IN}} = \text{GND to } 3.0\text{V}$

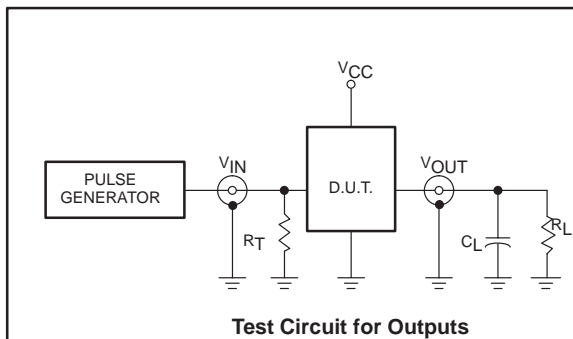


Waveform 1. Propagation Delay for Inverting Outputs

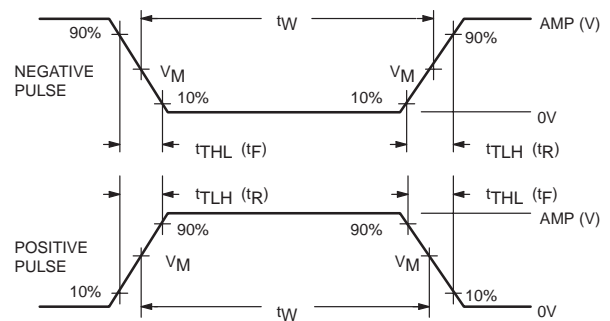


Waveform 2. Common edge skew

TEST CIRCUIT AND WAVEFORMS



Test Circuit for Outputs



$V_M = 1.5\text{V}$

Input Pulse Definition

DEFINITIONS

- R_L = Load resistor; see AC CHARACTERISTICS for value.
- C_L = Load capacitance includes jig and probe capacitance; see AC CHARACTERISTICS for value.
- R_T = Termination resistance should be equal to Z_{OUT} of pulse generators.

| FAMILY | INPUT PULSE REQUIREMENTS | | | | |
|--------|--------------------------|-----------|-------|-------|-------|
| | Amplitude | Rep. Rate | t_w | t_R | t_F |
| 74ABT | 3.0V | 1MHz | 500ns | 2.5ns | 2.5ns |

SH00067

Dual 4-input NAND gate

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DIP14: plastic dual in-line package; 14 leads (300 mil)

SOT27-1



DIMENSIONS (inch dimensions are derived from the original mm dimensions)

| UNIT | A max. | A ₁ min. | A ₂ max. | b | b ₁ | c | D ⁽¹⁾ | E ⁽¹⁾ | e | e ₁ | L | M _E | M _H | w | Z ⁽¹⁾ max. |
|--------|--------|---------------------|---------------------|----------------|----------------|----------------|------------------|------------------|------|----------------|--------------|----------------|----------------|-------|-----------------------|
| mm | 4.2 | 0.51 | 3.2 | 1.73 1.13 | 0.53 0.38 | 0.36 0.23 | 19.50 18.55 | 6.48 6.20 | 2.54 | 7.62 | 3.60 3.05 | 8.25 7.80 | 10.0 8.3 | 0.254 | 2.2 |
| inches | 0.17 | 0.020 | 0.13 | 0.068 0.044 | 0.021 0.015 | 0.014 0.009 | 0.77 0.73 | 0.26 0.24 | 0.10 | 0.30 | 0.14 0.12 | 0.32 0.31 | 0.39 0.33 | 0.01 | 0.087 |

Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

| OUTLINE VERSION | REFERENCES | | | EUROPEAN PROJECTION | ISSUE DATE |
|-----------------|------------|----------|------|---------------------|----------------------|
| | IEC | JEDEC | EIAJ | | |
| SOT27-1 | 050G04 | MO-001AA | | | 92-11-17 95-03-11 |

Dual 4-input NAND gate

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SO14: plastic small outline package; 14 leads; body width 3.9 mm

SOT108-1



DIMENSIONS (inch dimensions are derived from the original mm dimensions)

| UNIT | A max. | A ₁ | A ₂ | A ₃ | b _p | c | D ⁽¹⁾ | E ⁽¹⁾ | e | H _E | L | L _p | Q | v | w | y | Z ⁽¹⁾ | θ |
|--------|--------|----------------|----------------|----------------|----------------|------------------|------------------|------------------|-------|----------------|-------|----------------|----------------|------|------|-------|------------------|----------|
| mm | 1.75 | 0.25 0.10 | 1.45 1.25 | 0.25 | 0.49 0.36 | 0.25 0.19 | 8.75 8.55 | 4.0 3.8 | 1.27 | 6.2 5.8 | 1.05 | 1.0 0.4 | 0.7 0.6 | 0.25 | 0.25 | 0.1 | 0.7 0.3 | 8° 0° |
| inches | 0.069 | 0.010 0.004 | 0.057 0.049 | 0.01 | 0.019 0.014 | 0.0100 0.0075 | 0.35 0.34 | 0.16 0.15 | 0.050 | 0.244 0.228 | 0.041 | 0.039 0.016 | 0.028 0.024 | 0.01 | 0.01 | 0.004 | 0.028 0.012 | |

Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

| OUTLINE VERSION | REFERENCES | | | EUROPEAN PROJECTION | ISSUE DATE |
|-----------------|------------|----------|------|---------------------|----------------------|
| | IEC | JEDEC | EIAJ | | |
| SOT108-1 | 076E06S | MS-012AB | | | 95-01-29 97-05-22 |

Dual 4-input NAND gate

74ABT20

SSOP14: plastic shrink small outline package; 14 leads; body width 5.3 mm

SOT337-1



DIMENSIONS (mm are the original dimensions)

| UNIT | A max. | A ₁ | A ₂ | A ₃ | b _p | c | D ⁽¹⁾ | E ⁽¹⁾ | e | H _E | L | L _p | Q | v | w | y | Z ⁽¹⁾ | θ |
|------|--------|----------------|----------------|----------------|----------------|--------------|------------------|------------------|------|----------------|------|----------------|------------|-----|------|-----|------------------|----------|
| mm | 2.0 | 0.21 0.05 | 1.80 1.65 | 0.25 | 0.38 0.25 | 0.20 0.09 | 6.4 6.0 | 5.4 5.2 | 0.65 | 7.9 7.6 | 1.25 | 1.03 0.63 | 0.9 0.7 | 0.2 | 0.13 | 0.1 | 1.4 0.9 | 8° 0° |

Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

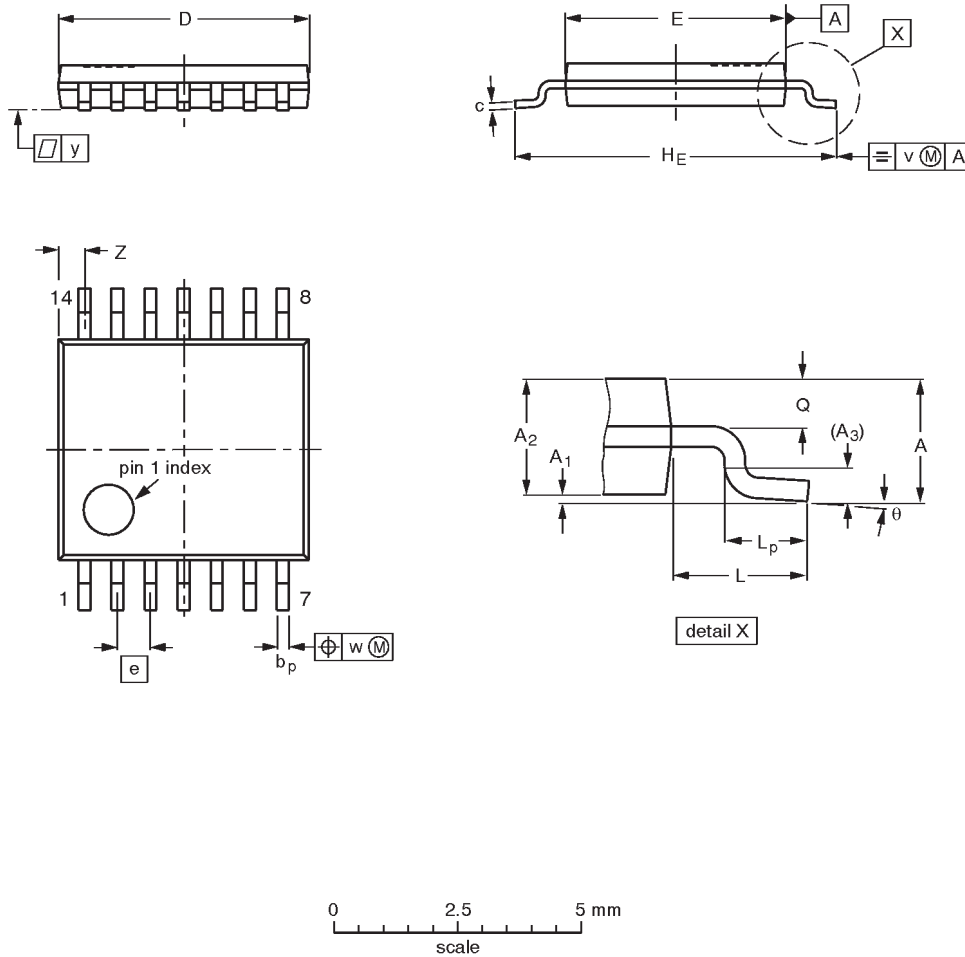
| OUTLINE VERSION | REFERENCES | | | | EUROPEAN PROJECTION | ISSUE DATE |
|-----------------|------------|----------|------|--|---------------------|---------------------------------|
| | IEC | JEDEC | EIAJ | | | |
| SOT337-1 | | MO-150AB | | | | 95-02-04 96-01-18 |

Dual 4-input NAND gate

74ABT20

TSSOP14: plastic thin shrink small outline package; 14 leads; body width 4.4 mm

SOT402-1



DIMENSIONS (mm are the original dimensions)

| UNIT | A max. | A ₁ | A ₂ | A ₃ | b _p | c | D ⁽¹⁾ | E ⁽²⁾ | e | H _E | L | L _p | Q | v | w | y | Z ⁽¹⁾ | θ |
|------|--------|----------------|----------------|----------------|----------------|------------|------------------|------------------|------|----------------|-----|----------------|------------|-----|------|-----|------------------|----------|
| mm | 1.10 | 0.15 0.05 | 0.95 0.80 | 0.25 | 0.30 0.19 | 0.2 0.1 | 5.1 4.9 | 4.5 4.3 | 0.65 | 6.6 6.2 | 1.0 | 0.75 0.50 | 0.4 0.3 | 0.2 | 0.13 | 0.1 | 0.72 0.38 | 8° 0° |

Notes

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.
2. Plastic interlead protrusions of 0.25 mm maximum per side are not included.

| OUTLINE VERSION | REFERENCES | | | | EUROPEAN PROJECTION | ISSUE DATE |
|-----------------|------------|--------|------|--|---------------------|------------------------|
| | IEC | JEDEC | EIAJ | | | |
| SOT402-1 | | MO-153 | | | | -94-07-12- 95-04-04 |

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NOTES

Dual 4-input NAND gate

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DEFINITIONS

| Data Sheet Identification | Product Status | Definition |
|----------------------------------|-------------------------------|--|
| <i>Objective Specification</i> | Formative or in Design | This data sheet contains the design target or goal specifications for product development. Specifications may change in any manner without notice. |
| <i>Preliminary Specification</i> | Preproduction Product | This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product. |
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